

Notice of References Cited

Application/Control No.

10/783,729

Applicant(s)/Patent Under
Reexamination
CHAN ET AL.

Examiner

John R. Hardee

Art Unit

1796

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,493,781	01-1985	Chapman et al.	510/278
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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